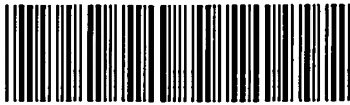


Search Notes

Application/Control No.

10/767,768

Examiner

Thomas D. Lee

Applicant(s)/Patent under
Reexamination

OGAWA, HIDEHIKO

Art Unit

2624

SEARCHED

Class	Subclass	Date	Examiner
358	1.15, 402, 440	6/7/2005	TDL
379	100.01	6/7/2005	TDL
379	100.08	6/7/2005	TDL
379	100.13	6/7/2005	TDL
379	100.17	6/7/2005	TDL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR